FDS2070N3 150V N-Channel PowerTrench[®] MOSFET

General Description

FAIRCHILD SEMICONDUCTOR

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low $R_{DS(ON)}$ in a small package.

Applications

- Synchronous rectifier
- DC/DC converter

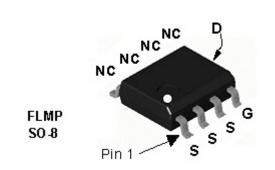
Features

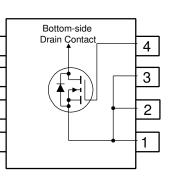
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- 4.1 A, 150 V. $R_{DS(ON)} = 78 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 88 \text{ m}\Omega @ V_{GS} = 6.0 \text{ V}$
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- · High power and current handling capability
- Fast switching, low gate charge (38nC typical)
- FLMP SO-8 package: Enhanced thermal performance in industry-standard package size





Absolute Maximum Ratings TA=25°C unless otherwise noted

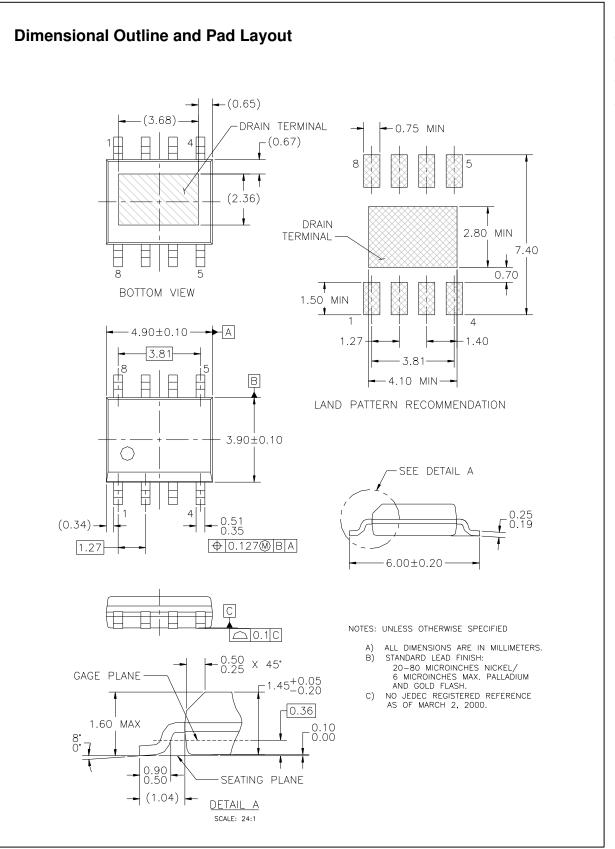
Symbol	Parameter			Ratings	Units
V _{DSS}	Drain-Source Voltage			150	V
V _{GSS}	Gate-Source Voltage			± 20	V
ID	Drain Curre	nt – Continuous	(Note 1a)	4.1	A
		 Pulsed 	30		
PD	Power Diss	ipation for Single Operation	n (Note 1a)	3.0	W
			(Note 1b)	1.8	
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C
Therma	I Charac	teristics			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1a)		40	°C/W	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)			0.5	
Packag	e Markin	g and Ordering I	nformation		
Device Marking		Device	Reel Size	Tape width	Quantity
FDS2070N3		FDS2070N3	13"	12mm	2500 units

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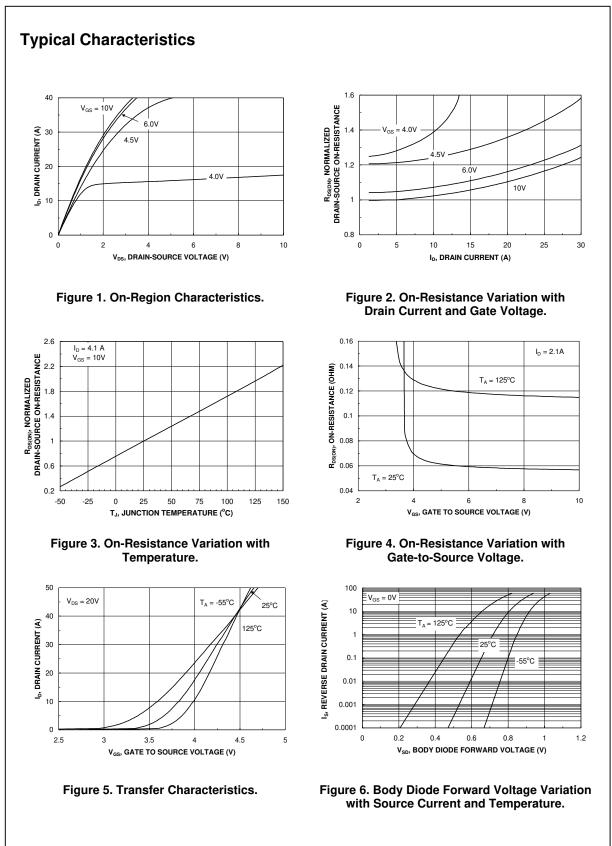
Avalanche Ratings n-Source Avalanche Energy n-Source Avalanche Current ristics n-Source Breakdown age akdown Voltage Temperature fficient o Gate Voltage Drain Current e-Body Leakage	Single Pulse, $V_{DD} = 150 \text{ V}$, $I_{D} = 10 \text{ A}$ L = 8.8 mH $V_{GS} = 0 \text{ V}$, $I_{D} = 250 \mu\text{A}$ $I_{D} = 250 \mu\text{A}$, Referenced to 25°C	150		440	mJ A
n-Source Avalanche Current 'istics n–Source Breakdown age akdown Voltage Temperature fficient o Gate Voltage Drain Current	L = 8.8 mH V _{GS} = 0 V, I_D = 250 μ A	150			
ristics n–Source Breakdown age akdown Voltage Temperature fficient o Gate Voltage Drain Current		150		10	A
n-Source Breakdown age akdown Voltage Temperature fficient o Gate Voltage Drain Current		150		1	
n-Source Breakdown age akdown Voltage Temperature fficient o Gate Voltage Drain Current		150		1	
fficient o Gate Voltage Drain Current	$I_D = 250 \ \mu\text{A}$, Referenced to 25°C				V
č			154		mV/°C
⊱Body Leakage	$V_{DS} = 120 V, V_{GS} = 0 V$			1	μA
	$V_{\text{GS}}=\pm20~V,~V_{\text{DS}}=0~V$			±100	nA
istics (Note 2)					
e Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	2	2.6	4	V
e Threshold Voltage	$I_D = 250 \ \mu\text{A}$, Referenced to 25°C		-7		mV/°C
ic Drain–Source Resistance	$ \begin{array}{l} V_{GS} = 10 \; V, I_D = 4.1 \; A \\ V_{GS} = 6.0 V, I_D = 3.8 \; A \\ V_{GS} = 10 \; V, I_D = 4.1 \; A, T_J = 125^\circ C \end{array} $		58 61 112	78 88 160	mΩ
vard Transconductance	$V_{DS} = 10 \text{ V}, I_D = 4.1 \text{ A}$		24		S
racteristics					
	$V_{DS} = 75 V, V_{GS} = 0 V,$		1884		pF
•	f = 1.0 MHz		102		pF
			35		pF
· ·	$V_{GS} = 15 \text{ mV}.$ f = 1.0 MHz		1.6		Ω
aractorictics w			1		<u> </u>
	$V_{DD} = 75 V$. $I_D = 1 A$.		10	20	ns
	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		-		ns
			-		ns
,			-	-	ns
	$V_{DS} = 75 V_{\odot} I_{D} = 4.1 A_{\odot}$				nC
0	$V_{GS} = 10 \text{ V}$				nC
-					nC
-	Delin a				110
		1		0.5	•
n-Source Diode Forward	$V_{GS} = 0 \text{ V}, I_S = 2.5 \text{ A} (\text{Note 2})$		0.75	1.2	A V
de Reverse Recovery Time	I _E = 4 1A		75		nS
le Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A}/\mu \text{s}$ (Note 2)		404		nC
	perature Coefficient ic Drain–Source Resistance vard Transconductance racteristics t Capacitance out Capacitance erse Transfer Capacitance e Resistance aracteristics (Note 2) –On Delay Time n–On Rise Time –Off Delay Time n–Off Fall Time Il Gate Charge e–Source Charge e–Drain Charge e–Drain Charge e Diode Characteristics imum Continuous Drain–Source n–Source Diode Forward age de Reverse Recovery Time de Reverse Recovery Charge	perature CoefficientValueic Drain–Source Resistance $V_{GS} = 10 \text{ V}$, $I_D = 4.1 \text{ A}$ $V_{GS} = 6.0 \text{ V}$, $I_D = 3.8 \text{ A}$ $V_{GS} = 10 \text{ V}$, $I_D = 4.1 \text{ A}$, $T_J = 125^{\circ}\text{C}$ vard Transconductance $V_{DS} = 10 \text{ V}$, $I_D = 4.1 \text{ A}$ racteristics t Capacitance erse Transfer Capacitance $V_{DS} = 75 \text{ V}$, $V_{GS} = 0 \text{ V}$, $f = 1.0 \text{ MHz}$ erse Transfer Capacitance e Resistance $V_{GS} = 15 \text{ mV}$, $f = 1.0 \text{ MHz}$ aracteristics (Note 2) i–On Delay Time i–Off Delay Time i–Off Delay Time i–Off Fall Time $V_{DD} = 75 \text{ V}$, $I_D = 1 \text{ A}$, $V_{GS} = 10 \text{ V}$, $R_{GEN} = 6 \Omega$ -Off Delay Time i–Off Characteristics and Maximum Ratingsimum Continuous Drain–Source Diode Forward Current n–Source Diode Forward Surrentn–Source Diode Forward age $V_{GS} = 0 \text{ V}$, $I_S = 2.5 \text{ A}$ (Note 2)e Reverse Recovery Time age $I_F = 4.1 \text{ A}$ $d_{iF}/d_t = 100 \text{ A}/\mu \text{s}$ (Note 2)unction-to-case and case-to-ambient thermal resistance where the case thermal reference i ranteed by design while R_{PCA} is determined by the user's board design.	perature Coefficientic Drain–Source $V_{GS} = 10$ V, $I_D = 4.1$ AResistance $V_{GS} = 6.0$ V, $I_D = 3.8$ A $V_{GS} = 10$ V, $I_D = 4.1$ A, $T_J = 125^{\circ}$ Cvard Transconductance $V_{DS} = 10$ V, $I_D = 4.1$ Aracteristicst Capacitance $V_{DS} = 75$ V, $V_{GS} = 0$ V,put Capacitancef = 1.0 MHzerse Transfer CapacitanceV_{GS} = 15 mV, f = 1.0 MHzaracteristics (Note 2)h-On Delay Time $V_{DD} = 75$ V, $I_D = 1$ A,h-On Rise Time $V_{GS} = 10$ V, $R_{GEN} = 6 \Omega$ -Off Delay Time $V_{DS} = 75$ V, $I_D = 4.1$ A,h-Off Fall Time $V_{DS} = 75$ V, $I_D = 4.1$ A,aracteristics (Note 2) $V_{DS} = 75$ V, $I_D = 4.1$ A,-Off Delay Time $V_{DS} = 75$ V, $I_D = 4.1$ A,-Off Fall Time $V_{DS} = 75$ V, $I_D = 4.1$ A,-Off Characteristics and Maximum Ratingsimum Continuous Drain–Source Diode Forward Currentn-Source Diode Forward $V_{GS} = 0$ V, $I_S = 2.5$ A (Note 2)agete Reverse Recovery Time $I_F = 4.1$ Ate Reverse Recovery Chargeunction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined a ranteed by design while R_{aCA} is determined by the user's board design.	perature CoefficientVGS = 10 V, ID = 4.1 A, VGS = 6.0V, ID = 3.8 A, VGS = 6.0V, ID = 3.8 A, VGS = 6.0V, ID = 3.8 A, VGS = 10 V, ID = 4.1 A, TJ = 125°C58ward TransconductanceVDS = 10 V, ID = 4.1 A, TJ = 125°C112ward TransconductanceVDS = 10 V, ID = 4.1 A, TJ = 125°C112racteristicsVDS = 75 V, VGS = 0 V, ID = 4.1 A, VDS = 0 V, ID = 4.1 A, ID	perature CoefficientVas = 10 V, I_D = 4.1 A58ic Drain-SourceVas = 0.0V, I_D = 4.1 A, T_J = 125°C112ResistanceVas = 10 V, I_D = 4.1 A, T_J = 125°C112vard TransconductanceV_Ds = 10 V, I_D = 4.1 A24racteristicst CapacitanceV_Ds = 75 V, V_{GS} = 0 V, I_D = 4.1 Abut Capacitancef = 1.0 MHz102erse Transfer Capacitancee ResistanceV_Gs = 15 mV, f = 1.0 MHzaracteristics (Note 2)-On Delay TimeV_DD = 75 V, I_D = 1 A,On V, Gs = 10 V, R_GEN = 6 Ω -On Delay TimeV_DS = 75 V, I_D = 1 A,-Off Delay TimeV_DS = 75 V, I_D = 4.1 A,38-Off Delay TimeV_DS = 75 V, I_D = 4.1 A,-Off Delay Time-Off Delay Time-Off Delay Time-Off Delay Time-Drain ChargeVBiode Characteristics and Maximum Ratingsimum Continuous Drain-Source Diode Forward Current2.5n-Source Diode Forward2.5NInterverse Recovery TimeInterverse Recovery TimeInterverse Recovery TimeInterverse Recovery ChargeInterverse Recovery ChargeInterver

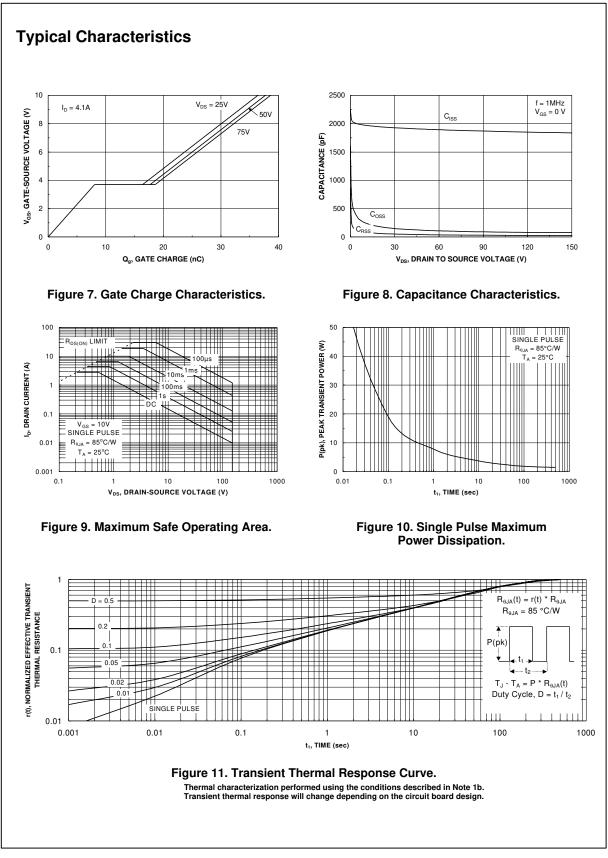
Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

FDS2070N3 Rev C(W)



FDS2070N3 Rev C(W)





FDS2070N3 Rev C(W)

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